Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/014,854	SHIOZAWA ET AL.
Examiner	Art Unit
Jason M. Perilla	2611

SEARCHED					
Class	Subclass	Date	Examiner		
375	316	9/2/2005	JP		
710	28	12/22/2005	JP		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
375	316	5/22/2006	JP	
375	354	5/22/2006	JP	
375	356	5/22/2006	JP	
375/357		5/22/2006	JP	

SEARCH (INCLUDING SEAF		')
	DATE	EXMR
East USPAT/USPGPUB	9/2/2005	JP
Inventor Name Search EAST/EDAN	12/22/2005	JP